


FORM PTO-1449		US DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE				Atty. Docket No. <b>84264AJLT</b> Customer No. 01333		Serial No. <b>10/621,968</b>	
If AFTER the later date of the first Office Action or 3 months from filing, use only with Rule 97(E) Certificate or Fee				Applicant: <b>Robert E. Dickerson, et al</b>					
LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)				Filing Date <b>17 July 2003</b>			Group <b>1752</b>		
<b>U.S. PATENT DOCUMENTS</b>									
Examiner Initial*	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE			
<b>h</b>	<b>6,348,293 b1</b>	<b>02/19/2002</b>	<b>Verbeeck et al</b>	<b>—</b>	<b>—</b>				
<b>FOREIGN PATENT DOCUMENTS</b>									
Examiner Initial*	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES NO			
<b>h</b>	<b>1 217 433 A2</b>	<b>26.06.2002</b>	<b>EPO</b>	<b>—</b>	<b>—</b>				<b>X</b>
<b>h</b>	<b>1 223 464 A2</b>	<b>17.07.2002</b>	<b>EPO</b>	<b>—</b>	<b>—</b>				<b>X</b>
<b>h</b>	<b>1 271 236 A2</b>	<b>02.01.2003</b>	<b>EPO</b>	<b>—</b>	<b>—</b>				<b>X</b>
<b>OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.)</b>									
EXAMINER <b>RL Schilling</b>				DATE CONSIDERED <b>5-17-04</b>					
<small>*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.</small>									

7-17-03

Sheet 1 of 1

<b>FORM PTO-1449</b> <b>US DEPARTMENT OF COMMERCE</b> <b>PATENT AND TRADEMARK OFFICE</b>		Atty. Docket No. <b>84264AJLT</b> Customer No. 01333		Serial No. <b>10/621968</b>	
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<b>LIST OF ART CITED BY APPLICANT</b> <small>(Use several sheets if necessary)</small>		Filing Date <b>7-17-03</b>		Group <b>1752</b>	

U.S. PATENT DOCUMENTS						
Examiner Initial*	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
W	4,659,654	04/21/1987	Metoki et al			
W	4,710,637	12/01/1987	Luckey et al			
W	4,937,180	06/26/1990	Marchetti et al			
W	4,945,035	07/31/1990	Keevert, Jr. et al			
W	5,455,139	10/03/1995	Wada et al			
W	5,494,789	02/27/1996	Daubendiek et al			
W	5,503,970	04/02/1996	Olm et al			
W	5,503,971	04/02/1996	Daubendiek et al			
W	5,558,981	09/24/1996	Bayley			
W	5,738,981	04/14/1998	Dickerson et al			
W	5,759,754	06/02/1998	Dickerson			
W	5,853,967	12/29/1998	Dickerson			
W	5,998,083	12/07/1999	Verbeeck et al			
W	6,033,840	03/07/2000	Dickerson			
W	6,037,112	03/14,2000	Dickerson			
W	6,277,552	08/21/2001	Elst et al			

FOREIGN PATENT DOCUMENTS						
Examiner Initial*	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES NO

OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.)	
W	USSN 10/ 299,936 filed 11/19/2002, titled <i>Radiographic Film With Improved Signal detection For Mammography</i> , by Adin et al
W	USSN 10/ 299,458 filed 11/19/2002, titled <i>Radiographic Mammography Film Having Improved Processability, Imaging Assembly And Method of Imaging</i> by Adin et al
W	USSN 10/ 299,765 filed 11/19/2002, titled <i>Mammography Film And Imaging Assembly For Use With Rhodium or Tungsten Anodes</i> , by Dickerson et al.
W	USSN 10/ 299,941 filed 11/19/2002 on even date herewith, titled <i>Mammography Imaging Method Using High Peak Voltage</i> , by Dickerson et al.
W	USSN 10/ 299,759 filed 11/19/2002, titled <i>Mammography Imaging Method Using High Peak Voltage and Rhodium Or Tungsten Anodes</i> , by Dickerson et al.
W	USSN 10/299,475 filed 11/19/2002, titled <i>High Bromide Cubic Grain Emulsions</i> , by Adin et al.

EXAMINER <b>A L Schell</b>	DATE CONSIDERED <b>5-18-04</b>
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